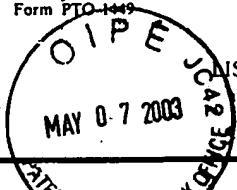
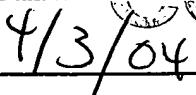


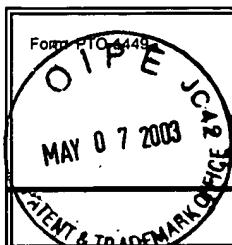
Form PTO-1449  <b>LIST OF ART CITED BY APPLICANT</b> (Use several sheets if necessary)		<b>U.S. DEPARTMENT OF COMMERCE</b> <b>PATENT AND TRADEMARK OFFICE</b>		ATTY. DOCKET NO. M122-1898	SERIAL NO. 10/050,348	
				APPLICANT Gurtej S. Sandhu et al.		
				FILING DATE January 15, 2002	GROUP 2813	
		<b>U.S. PATENT DOCUMENTS</b>				
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
AA	5,972,800	10/99	Hasegawa			
AB	6,146,948	11/00	Wu et al.			
AC						
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AF						
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AH						
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<b>FOREIGN PATENT DOCUMENTS</b>						
	Document Number	Date	Country	Class	Subclass	Translation
AM						Yes
AN						No
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<b>OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)</b>						
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EXAMINER 		DATE CONSIDERED 				
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Form PTO-1449 O I P E J C 2 MAY 07 2003		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI22-1898		SERIAL NO. 10/050,348	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)			APPLICANT Gurtej S. Sandhu et al.					
			FILING DATE January 15, 2002			GROUP 2813		
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name		Class	Subclass	Filing Date If Appropriate
	AA	5,837,598	11/1998	Aronowitz et al.				
	AB	6,450,116	09/2002	Noble et al.				
	AC	4,605,447	08/1986	Brotherton et al.				
	AD	6,207,586	03/2001	Ma et al.				
	AE	5,837,592	11/1998	Chang et al.				
	AF	5,334,554	08/1994	Lin et al.				
	AG	6,297,162	10/2001	Jang et al.				
	AH							
	AI							
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FOREIGN PATENT DOCUMENTS								
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
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MI22-1898SERIAL NO.  
10/050,348APPLICANT  
Gurtej S. Sandhu et al.FILING DATE  
Jan. 15, 2002 (RCE filed herewith)GROUP  
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*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
SL	AA	6,093,661	07/00	Trivedi, et al.			
SL	AB	5,994,749	11/99	Oda			
SL	AC	5,674,788	10/97	Wristers, et al.			
SL	AD	5,596,218	01/97	Soleimani, et al.			
SL	AE	5,960,302	09/99	Ma et al.			
SL	AF	6,207,532 B1	03/01	Lin et al.			
SL	AG	6,114,203	09/00	Ghidini, et al.			
SL	AH	6,110,842	08/00	Okuno et al.			
SL	AI	6,091,110	07/00	Hebert et al.			
SL	AJ	5,330,920	07/94	Soleimani, et al.			
SL	AK	6,140,187	10/00	DeBusk et al.			
SL	AL	6,197,701	03/01	Shue et al.			

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## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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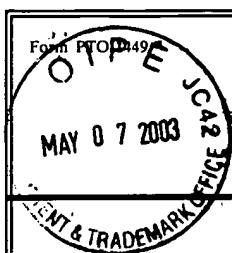
EXAMINER  
*Hebert et al.*

DATE CONSIDERED

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MI22-1898SERIAL NO.  
10/050,348LIST OF ART CITED BY APPLICANT  
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Jan. 15, 2002 [RCE filed herewith]GROUP  
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*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>SL</i>	AA	6,331,492 B2	12/01	Misium et al.			
<i>SL</i>	AB	6,080,629	06/00	Gardner et al.			
<i>SL</i>	AC	5,970,345	10/99	Hattangady et al.			
<i>SL</i>	AD	5,885,877	03/99	Gardner et al.			
<i>SL</i>	AE	6,323,114 B1	11/01	Hattangady et al.			
<i>SL</i>	AF	6,184,110 B1	02/01	Ono et al.			
<i>SL</i>	AG	6,436,771 B1	08/02	Jang et al.			
<i>SL</i>	AH	6,413,881 B1	07/02	Aronowitz et al.			
<i>SL</i>	AI	6,110,780	08/00	Yu et al.			
<i>SL</i>	AJ	5,861,651	01/99	Brasen et al.			
<i>SL</i>	AK	5,840,610	11/98	Gilmer et al.			
<i>SL</i>	AL	5,500,380	03/96	Kim			
<i>SL</i>	AM	6,410,991 B1	06/02	Kawai et al.			
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<i>SL</i>	AO	6,492,690 B2	12/02	Ueno et al.			

## FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
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## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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EXAMINER	<i>Naresh Schetty</i>	DATE CONSIDERED	<i>3/30/04</i>
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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Gurtej S. Sandhu et al.				
				FILING DATE Jan. 15, 2002 [RCE filed herewith]		GROUP 2813		
U.S. PATENT DOCUMENTS								
*Examiner Initial	Document Number	Date	Name		Class	Subclass	Filing Date If Appropriate	
AA	US 2003/0034518 A1	Pub. 02/20/03	Yoshikawa					
AB								
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
AR							RECEIVED MAY 13 2003 TECHNOLOGY CENTER 2800	
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EXAMINER <i>hanna shelby</i>	DATE CONSIDERED 4/3/04							
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